



BILLING CODE 3510-DS-P

DEPARTMENT OF COMMERCE

International Trade Administration

Max Planck Florida Institute, et al.

Notice of Consolidated Decision on Applications
for Duty-Free Entry of Electron Microscope

This is a decision consolidated pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, as amended by Pub. L. 106-36; 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 A.M. and 5:00 P.M. in Room 3720, U.S. Department of Commerce, 14th and Constitution Avenue, NW, Washington, D.C.

Docket Number: 11-061. Applicant: Max Planck Florida Institute, Jupiter, FL 33458. Instrument: Electron Microscope. Manufacturer: FEI Company, Czech Republic. Intended Use: See notice at 77 FR 5767, February 6, 2012.

Docket Number: 11-070. Applicant: University of Utah,

Salt Lake City, UT 84112. Instrument: Electron
Microscope. Manufacturer: FEI Company, Czech Republic.
Intended Use: See notice at 77 FR 5767, February 6, 2012.

Docket Number: 11-071. Applicant: Texas Tech University,
Lubbock, TX 79409-3103. Instrument: Electron Microscope.
Manufacturer: Hitachi High-Technologies Corporation, Japan.
Intended Use: See notice at 77 FR 5767, February 6, 2012.

Docket Number: 11-073. Applicant: Ball State University,
Muncie, IN 47306. Instrument: Electron Microscope.
Manufacturer: JEOL Ltd., Japan. Intended Use: See notice
at 77 FR 5767, February 6, 2012.

Docket Number: 11-075. Applicant: Cleveland State
University, Cleveland, OH 44115-2214. Instrument:
Electron Microscope. Manufacturer: FEI Company, Czech
Republic. Intended Use: See notice at 77 FR 5767,
February 6, 2012

Docket Number: 12-003. Applicant: University of
California, Irvine, Irvine, CA 92697. Instrument: Electron
Microscope. Manufacturer: FEI Company, Czech Republic.
Intended Use: See notice at 77 FR 5767, February 6, 2012.

Comments: None received. Decision: Approved. No instrument of equivalent scientific value to the foreign instrument, for such purposes as this instrument is intended to be used, is being manufactured in the United States at the time the instrument was ordered. Reasons: Each foreign instrument is an electron microscope and is intended for research or scientific educational uses requiring an electron microscope. We know of no electron microscope, or any other instrument suited to these purposes, which was being manufactured in the United States at the time of order of each instrument.

Gregory W. Campbell
Director
Subsidies Enforcement Office
Import Administration

March 5, 2012
Date

[FR Doc. 2012-5934 Filed 03/09/2012 at 8:45 am; Publication
Date: 03/12/2012]